

N-Channel Enhancement Mode MOSFET

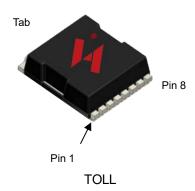
Feature

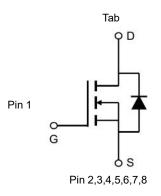
- 135V/226A
 R_{DS(ON)}=3.5 mΩ(typ.)@Ves = 10V
- 100% Avalanche Tested
- Reliable and Rugged
- Halogen-Free Devices Available (RoHS Compliant)

Applications

- Switching application
- Battery management

Pin Description





N-Channel MOSFET

Ordering and Marking Information



Package Code

TA:TOLL

Date Code

XYMXXXXXX

Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)			1
VDSS	Drain-Source Voltage		135	V
Vgss	Gate-Source Voltage		±20	V
TJ	Junction Temperature Ran	ige	-55 to 175	°C
Тѕтс	Storage Temperature Ran	ge	-55 to 175	°C
ls	Source Current-Continuous(Body Diode)	Tc=25°C	226	А
Mounted on	Large Heat Sink	,		
lом	Pulsed Drain Current *	Tc=25°C	700	А
1_	Continuous Drain Current	Tc=25°C	226	А
lσ	Continuous Drain Current	Tc=100°C	159	А
Б	Marrian David Diagraphy	Tc=25°C	405	W
Po	Maximum Power Dissipation Tc=100°C		202	W
R₀JC	Thermal Resistance, Junction-to-Case	0.37	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		45	°C/W
Eas	SinglePulsed-Avalanche Energy *** L=0.3mH		936.5	mJ

Note: * Repetitive rating; pulse width limited by max.junction temperature.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

Cymbal	Parameter	Test Conditions	HY	HYG050N13NS1		Unit	
Symbol	Parameter	rest Conditions	Min	Тур.	Max	Unit	
Static Char	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} = 250μA	135	-	-	V	
Design to Course Looks as Course		V _{DS} =135V,V _{GS} =0V	-	-	1	μA	
loss	Drain-to-Source Leakage Current	TJ=125°0	-	-	50	μA	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} = 250μA	2	3.3	4	V	
Igss	Gate-Source Leakage Current	Vgs=±20V,Vps=0V	-	-	±100	nA	
RDS(ON)	Drain-Source On-State Resistance	V _{GS} = 10V,I _{DS} =50A	-	3.5	4.4	mΩ	
Diode Char	Diode Characteristics						
VsD	Diode Forward Voltage	IsD=50A,VGS=0V	-	0.83	1.3	V	
trr	Reverse Recovery Time	Isp=50A,dIsp/dt=100A/µs	-	100.8	-	ns	
Qrr	Reverse Recovery Charge	15D-30A, UISD/UI-100A/µS	-	316.9	-	nC	

^{**} Surface mounted on 1in2 FR-4 board.

^{***} Limited by T_Jmax , starting T_J=25°C, L = 0.3mH, R_G= 25Ω , V_GS =10V.

HYG050N13NS1TA



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Cumbal	Do worm of our	Toot Conditions	HYG050N13N	NS1	l lm!4	
Symbol	Parameter	Test Conditions	Min	Тур.	Max	Unit
Dynamic	Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	-	2.7	-	Ω
Ciss	Input Capacitance	V _G S=0V,	-	10800	-	
Coss	Output Capacitance	V _{DS} = 25V,	-	2628	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	141	-	
td(ON)	Turn-on Delay Time		-	30.9	-	
Tr	Turn-on Rise Time	V _{DD} = 68V,R _G =2.5Ω,	-	98.6	-	
td(OFF)	Turn-off Delay Time	Ips= 50A,Vgs= 10V	-	88.9	-	ns
Tf	Turn-off Fall Time		-	89.1	-	
Gate Charge Characteristics						
Qg	Total Gate Charge		-	161.2	-	
Qgs	Gate-Source Charge	V _{DS} =108V, V _{GS} =10V,I _{Ds} =50A	-	57.5	-	nC
Qgd	Gate-Drain Charge		-	34.6	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

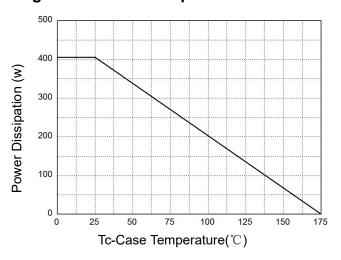


Figure 3: Safe Operation Area

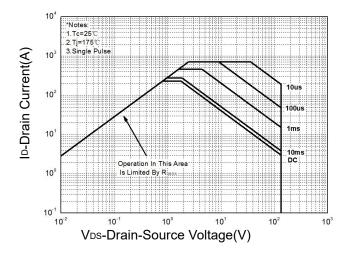


Figure 5: Output Characteristics

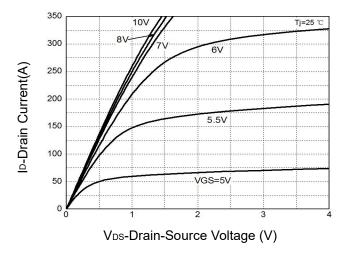


Figure 2: Drain Current

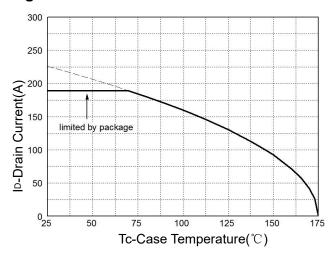


Figure 4: Thermal Transient Impedance

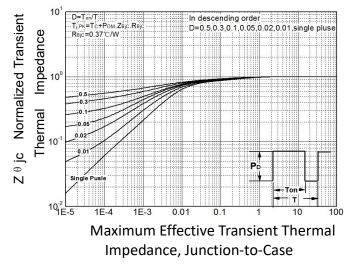
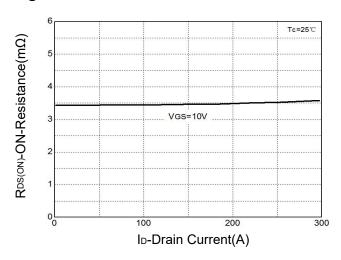


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

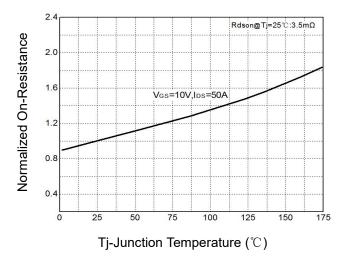


Figure 9: Capacitance Characteristics

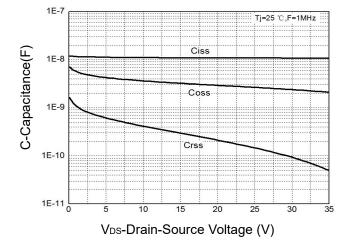


Figure 8: Source-Drain Diode Forward

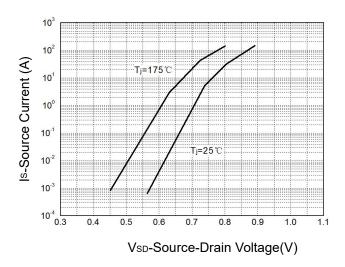
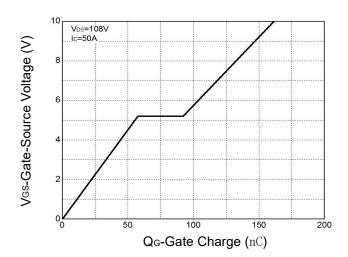
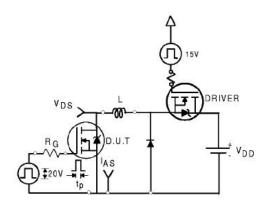


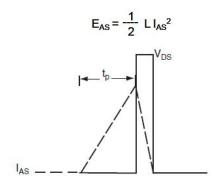
Figure 10: Gate Charge Characteristics



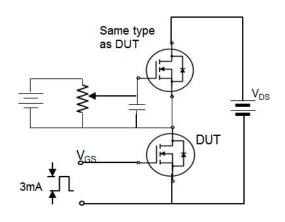


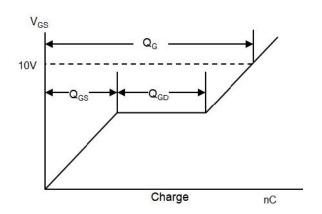
Avalanche Test Circuit



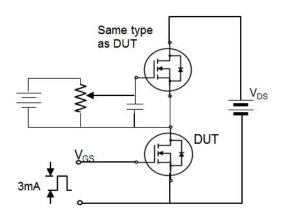


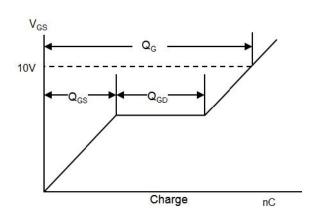
Switching Time Test Circuit





Gate Charge Test Circuit





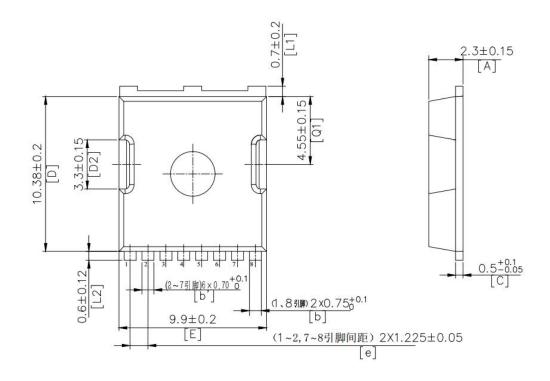


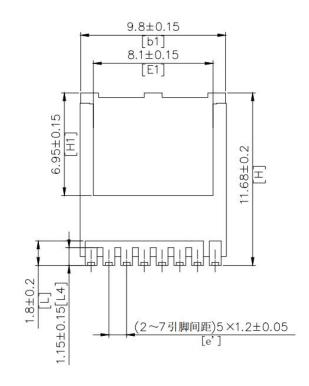
Device Per Unit

Package Type	Unit	Quantity
TOLL	Reel	1200

Package Information

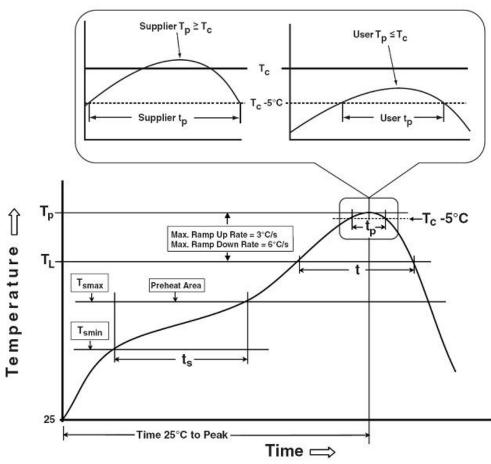
TOLL







Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly		
Preheat & Soak	100 °C	150 °C		
Temperature min (T _{smin})				
Temperature max (T _{smax})	150 °C	200 °C		
Time (Tsmin to Tsmax) (t _s)	60-120 seconds	60-120 seconds		
Average ramp-up rate	2 ° 0 /	3°C/second max.		
(T _{smax} to T _P)	3 °C/second max.			
Liquidous temperature (T₋)	183 °C	217 °C		
Time at liquidous (t∟)	60-150 seconds	60-150 seconds		
Peak package body Temperature	See Classification Temp in table 1	SecClessification Tempin table 2		
(T _p)*	See Classification Temp in table 1	SeeClassification Tempin table 2		
Time (t _P)** within 5°C of the specified	20**	20**		
classification temperature (T₀)	20** seconds	30** seconds		
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.		
Time 25°C to peak temperature	6 minutes max.	8 minutes max.		
*Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.				

^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

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Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
PRECON	JESD-22, A113	85°C/85%RH,168Hrs
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000Hrs, Vgs100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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